

THE UNIVERSITY OF TEXAS AT AUSTIN

CHE323/CHE384
Chemical Processes for Micro- and Nanofabrication

Lecture 10 Thermal Oxidation, part 1

Chris A. Mack
Adjunct Associate Professor

Reading:
Chapter 4, *Fabrication Engineering at the Micro- and Nanoscale*, 4th edition, Campbell

© Chris Mack, 2013 (some images obtained from Wikimedia Commons) 1

THE UNIVERSITY OF TEXAS AT AUSTIN

Silicon Dioxide

- Two Main purposes of SiO₂:
 - Electrical insulator
 - Dopant diffusion barrier
- Used in the process at these steps:
 - Device isolation (LOCOS or STI)
 - Gate Oxide
 - Poly gate spacer (for LDD)
 - Interlayer dielectric (ILD) for metal levels
 - Sacrificial oxide
- Deposition Methods:
 - Thermal growth
 - Chemical Vapor Deposition (CVD)

© Chris Mack, 2013 2

THE UNIVERSITY OF TEXAS AT AUSTIN

Thermal Oxidation

- Oxide is “grown” by supplying an oxygen source that reacts with the silicon wafer at high temperatures to form SiO₂ at the wafer surface
- Thermal oxides are valuable because they are:
 - Stable, intrinsically good insulators
 - Very clean/pure when thermally grown
 - Have excellent Si/SiO₂ interface with low electrical defects (good for gate oxide)

© Chris Mack, 2013 3

THE UNIVERSITY OF TEXAS AT AUSTIN

Oxidation Furnace

© Chris Mack, 2013 4

THE UNIVERSITY OF TEXAS AT AUSTIN

Temperature Control

Dummy wafers at ends of boat

±0.5 °C temp. control required

600 – 1200 °C range for furnace

© Chris Mack, 2013 5

THE UNIVERSITY OF TEXAS AT AUSTIN

Thermal Cycle

Temp

1000°C

750°C

Time

Push, N₂ + 5% O₂

Ramp Up, N₂ + 5% O₂

Oxidation, O₂ + HCl

Ramp Down, N₂

Pull, N₂

© Chris Mack, 2013 6

THE UNIVERSITY OF TEXAS
AT AUSTIN

WHAT STARTS HERE CHANGES THE WORLD

Thermal Oxidation Cycle

- Push
 - Low temp to reduce thermal stress (wafer warpage)
 - O_2 included to prevent nitride formation
- Dry Oxidation
 - $O_2 + HCl$
 - Slow, used for thin oxides or where high quality is required
- Wet Oxidation
 - $O_2 + H_2O$
 - Fast, used for thick oxides
- N_2 Anneal
 - Reduces surface states
- Ramp down and Pull
 - Low Stress, low surface states, low fixed charge

© Chris Mack, 2013 7

THE UNIVERSITY OF TEXAS
AT AUSTIN

WHAT STARTS HERE CHANGES THE WORLD

Electrical Defects

© Chris Mack, 2013 8

THE UNIVERSITY OF TEXAS
AT AUSTIN

WHAT STARTS HERE CHANGES THE WORLD

Quality Control

- Mobile Ions – introduced by contamination
 - Use good pre-clean
 - Careful backside handling
 - Clean furnace components
 - Use HCl during oxidation (Cl reacts with mobile ions; results in excess Cl in oxide film)
- Interface States – fixed charge and interface trapped charge
 - Avoid stress, which causes oxide-induced stacking faults
 - Use N_2 or Ar during pull
 - Use HCl during oxidation
- Thickness Control
 - Across wafer, wafer-to-wafer, and lot-to-lot
 - Vertical furnaces have better temperature uniformity

© Chris Mack, 2013 9

THE UNIVERSITY OF TEXAS
AT AUSTIN

WHAT STARTS HERE CHANGES THE WORLD

Lecture 10: What have we learned?

- What is oxide used for in a CMOS process?
- What are the advantages of thermal oxidation?
- Explain the basic workings of an oxidation furnace
- Why is HCl used in the oxidation process?
- How does one insure good oxide thickness uniformity?

© Chris Mack, 2013 10